Park NX12

The most versatile AFM platform for your nanoscale microscopy needs

- Atomic Force Microscopy (AFM) for nanometer resolution imaging with electrical, magnetic, thermal, and mechanical property measurement capabilities
- Pipette-based scanning system for high resolution Scanning Ion Conductance Microscopy (SICM)
- Inverted Optical Microscopy (IOM) for transparent material research and fluorescence microscopy integration

www.parksystems.com
The perfect platform for fundamental electrochemistry

The study of the electrochemistry of batteries, fuel cells, sensors, and corrosion is a rapidly growing field, yet many AFMs do not directly address its unique needs. Park NX12 offers the functionality and flexibility chemistry researchers require by giving them one simple, easy-to-use platform with all the tools they need including:

- Versatile and easy-to-use electrochemistry cells
- Environmental control options for inert gas and humidity
- Bi-potentiostat compatibility

Researchers can utilize the Park NX12 platform for various electrochemical applications:

- Scanning Electrochemical Microscopy (SECM)
- Scanning Electrochemical Cell Microscopy (SECCM)
- Electrochemical Atomic Force Microscopy (EC-AFM) and Electrochemical Scanning Tunneling Microscopy (EC-STM)

Easy optical access with motorized focus stage

The system allows for top, side, and bottom optical access to the probe from various angles during measurements. This broad optical access combined with the device’s modular design also allows for the addition of optical or nano-optical add-ons.

Park NX12 couples the versatility and accuracy of Park AFM with a sample stage for inverted optical microscopy. This allows users to easily set up pipette-based techniques and work with samples that are transparent or opaque and soft or hard.
Built with multi-user facilities in mind

Park NX12 was built from the ground up to accommodate the needs of multi-user facilities. Other AFM solutions lack the required versatility to address the diverse needs of users in these facilities, making it difficult to justify the equipment cost. The Park NX12, however, is built to accommodate standard ambient AFM, in-liquid SPM, optical, and nano-optical imaging, making it one of the most flexible AFMs available.

A modular platform for shared user facilities

- The Park NX12 is an AFM platform specifically tailored to address the needs of analytical and electrochemistry researchers as well as others working in shared use facilities.
- It provides a versatile solution for SPM-based characterization of chemical and electrochemical properties and surface characterization in both air and liquid media for a broad range of opaque and transparent materials.
- The Park NX12 is easy to use for pipette-based SPM techniques with broad visual optical access to the scanning probe.
- The Park NX12’s reasonable price and unparalleled accuracy makes it the ideal platform for multi-user facilities as well as early career researchers.

Multiple applications

The Park NX12 can serve a wide range of functions, including PinPoint™ in-liquid and nanomechanical mapping, inverted optical microscopy to locate transparent samples, SICM for imaging ultra-soft samples, and enhanced vision to improve optics for transparent samples.

Multiple applications

- PinPoint™ mode
- Height (PinPoint)
- Adhesion
- Modulus
- Stiffness

- SICM

- Comprehensive force spectroscopy solution

The Park NX12 provides a complete package for nanomechanical characterization in-liquid and in-air, making it ideal for a wide range of applications.

- Modular

We make it easy to modify the Park NX12 to suit the unique needs of your lab by installing optional hardware and software add-ons even after installation.
Park NX12
Why the world’s most accurate small sample AFM is also the easiest to use

Easy tip and sample exchange
The unique head design allows easy side access allowing you to easily snap new tips and samples into place by hand. The cantilever is ready for scanning without the need for any tricky laser beam alignment by using pre-aligned cantilevers mounted on to the cantilever tip holder.

Lightning fast automatic tip approach
Our automatic tip-to-sample approach requires no user intervention. By monitoring the cantilever’s response to the approaching surface, Park NX12 can initiate and complete an automatic fast tip-to-sample approach within 10 seconds of the cantilever’s loading. Fast feedback by the high-speed Z-scanner and low-noise signal processing by the NX electronics controller enable quick engagement to the sample surface without any user intervention. It just works; minimal user involvement is required.

Easy, intuitive laser beam alignment
With our advanced pre-aligned cantilever holder, the laser beam is focused on the cantilever upon placement. Furthermore, the natural on-axis, top-down view—the only one in the industry—allows you to easily find the laser spot. Since the laser beam falls vertically onto the cantilever, you can intuitively move the laser spot along the X- and Y-axes by rotating two positioning knobs. As a result, you can easily find the laser and position it onto the position-sensitive photodiode using our operation software’s beam alignment user interface. From there, all you will need is a minor adjustment to maximize the signal prior to starting data acquisition.

Single-click imaging with Park SmartScan™ Auto mode
All you need to specify for AFM imaging are your quality-speed preference, the target pixel density, and scan size. Outside of those factors, you can leave all sophisticated AFM parameters up to the Auto mode of Park SmartScan™. The system will start a measurement with optimized conditions for automatic imaging at the click of a button.

An AFM OS for everyone, from amateurs to experts
Whether your AFM needs are focused on academic research, industrial metrology or failure analysis, SmartScan’s Auto mode offers a streamlined system to generate publishable high quality AFM data. Moreover, SmartScan™ promises productive sessions with an AFM even for beginners to obtain quality data as good as an expert’s, in much shorter time.

FastApproach™
Click the Position button and the Z scanner approaches the sample automatically and at a much higher speed than the typical manual approach. Park’s patented FastApproach™ safely takes the probe down to the sample surface at full speed without the user’s intervention and engages 10 seconds after the cantilever is loaded.

Easy to find an area of interest
After tip-to-sample engagement, the optical camera will automatically focus on the sample to find your area of interest, allowing intuitive navigation of the sample by giving users control of the AFM’s motorized stages in the integrated optical view window.

Speeds up imaging with AdaptiveScan™
Park’s innovative AdaptiveScan™ controls the scan speed automatically based on the peaks and valleys of the sample surface. AdaptiveScan™ adjusts the optimum scan speed dynamically to acquire a quality image of an unknown morphology at a higher speed. This effectually shortens the imaging time while retaining top-image quality comparable to that obtained by a well-trained expert manually. When moving to neighboring locations or zooming-in to a target, AdaptiveScan automatically applies a new optimal condition.
Park NX12
Adaptable to any project

The wide range of scanning modes and modular design of the NX series allows it to be easily tailored to the needs of any scanning probe microscopy project.

Standard Imaging
- True Non-Contact AFM
- Basic Contact AFM
- Lateral Force Microscopy (LFM)
- Phase Imaging
- Intermittent (tapping) AFM

Chemical Properties
- Scanning Electrochemical Cell Microscopy (CECCM)
- Scanning Electrochemical Microscopy (ECM)
- Electrochemical Microscopy (EC-STM and EC-AFM)
- Chemical Force Microscopy with Functionalized Tip

Thermal Properties
- Scanning Thermal Microscopy (SThM)

Mechanical Properties
- PinPoint Nanomechanical Mapping
- Force Modulation Microscopy (FMM)
- Nanosindentation
- Nanolithography
- Nanotribography

Electrical Properties
- Conductive AFM
- I-V Spectroscopy
- Kelvin Probe Force Microscopy (KPFM)
- KPFM with High Voltage
- Scanning Capacitance Microscopy (SCM)
- Scanning Spreading Resistance Microscopy (SSRM)
- Scanning Tunneling Microscopy (STM)
- Scanning Tunneling Spectroscopy (STS)
- Time-Resolved Photo Current Mapping (Tr-PCM)

Dielectric/Piezoelectric Properties
- Electric Force Microscopy (EFM)
- Dynamic Contact EFM (DC-EFM)
- Piezoelectric Force Microscopy (PFM)
- PFM with High Voltage

Optical Properties
- Tip-Enhanced Raman Spectroscopy (TERS)
- Time-Resolved Photo Current Mapping (Tr-PCM)

Magnetic Properties
- Magnetic Force Microscopy (MFM)
- Tunable MFM

Electrochemistry Options
- Potentiostat
- Bi-potentiostat
- Electrochemistry toolkit for universal liquid cell
- Electrochemistry cell

Environmental Control Options
- Glovebox
- Live cell chamber
- Temperature Controlled Stages
- Temperature controlled stage (-25 ~ 180 ºC)
- 250 ºC heating stage
- 600 ºC heating stage
- Magnetic Field Generator
- Applies external magnetic field parallel to sample surface
- Tunable magnetic field
- Range: ~ 300 gauss

Z Scanner Heads
- 15 µm Z Scanner AFM head
- 30 µm Z Scanner AFM head
- 15 µm Z Scanner SICM module
- 30 µm Z Scanner SICM module

In-Liquid Imaging Options
- Liquid probe hand
- Open liquid cell
- Universal liquid cell

Clip-type Chip Carrier
- Can be used with unmounted cantilever
- Tip bias function available for conductive AFM and EFM
- Tip bias range: -10 V ~ 10 V

Starter kits for advanced modes
- Easy to use for advanced modes
- Includes specialized probes and samples

Options
A wide range of environment control options including versatile electrochemistry cells, temperature stage, and glovebox with humidity control.
## Park NX12 Specification

<table>
<thead>
<tr>
<th>Scanner</th>
<th>Z scanner</th>
<th>XY scanner</th>
<th>Dimensions in mm</th>
</tr>
</thead>
<tbody>
<tr>
<td><strong>APM Head</strong></td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>Flexure-guided high-force scanner</td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>Scan range: 15 µm (optional 30 µm)</td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td><strong>UCM Head</strong></td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>Flexure-guided structure driven by multi-layer piezoelectric actuator</td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>Scan range: 15 µm (optional 30 µm)</td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td><strong>GloveBox</strong> Optional</td>
<td></td>
<td></td>
<td></td>
</tr>
</tbody>
</table>

<table>
<thead>
<tr>
<th>Stage</th>
<th>Vision</th>
<th>Inverted Optical Microscopy</th>
</tr>
</thead>
<tbody>
<tr>
<td>XY stage travel range: 50 mm x 50 mm</td>
<td>Direct on-axis view of sample surface and cantilever field of view: 684 µm x 600 µm with 10 x objective lens</td>
<td>Objective lens: Up to 10x</td>
</tr>
<tr>
<td>2 stage travel range: 25 mm</td>
<td></td>
<td>Fluorescence microscopy (optional)</td>
</tr>
<tr>
<td>Focus stage travel range: 15 mm</td>
<td></td>
<td>Confocal microscopy (optional)</td>
</tr>
<tr>
<td></td>
<td></td>
<td></td>
</tr>
</tbody>
</table>

<table>
<thead>
<tr>
<th>Electronics</th>
<th>Signal processing</th>
<th>Integrated functions</th>
</tr>
</thead>
<tbody>
<tr>
<td>ADC: 18 channels</td>
<td>24-bit ADCs for X, Y, and Z scanner positioner</td>
<td>3 channels of digital lock-in amplifier</td>
</tr>
<tr>
<td>DAC: 12 channels</td>
<td>20-bit DACs for X, Y, and Z scanner positioning</td>
<td>Spring constant calibration (thermal vibration method)</td>
</tr>
</tbody>
</table>

<table>
<thead>
<tr>
<th>Options/Modes</th>
<th>Standard Imaging</th>
<th>Chemical Properties</th>
<th>Dielectric/Piezoelectric Properties</th>
</tr>
</thead>
<tbody>
<tr>
<td><strong>True Non-contact™ Mode</strong></td>
<td>SECM</td>
<td>Electric Force Microscopy (EFM)</td>
<td></td>
</tr>
<tr>
<td><strong>Basic Contact Mode</strong></td>
<td>SCM</td>
<td>Dynamic Contact EFM (EFM-DC)</td>
<td></td>
</tr>
<tr>
<td><strong>Lateral Force Microscopy (LFM)</strong></td>
<td>EC-AFM and EC-STM</td>
<td>Piezoelectric Force Microscopy (PFM)</td>
<td></td>
</tr>
<tr>
<td><strong>Phase Imaging Mode</strong></td>
<td>Chemical force microscopy with Functionalized Tip</td>
<td>PFM with High Voltage</td>
<td></td>
</tr>
<tr>
<td><strong>Tapping Mode</strong></td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td><strong>PhoPin™ Mode: PhoPin imaging</strong></td>
<td></td>
<td></td>
<td></td>
</tr>
</tbody>
</table>

<table>
<thead>
<tr>
<th>Force Measurement</th>
<th>Magnetic Properties</th>
<th>Thermal Properties</th>
</tr>
</thead>
<tbody>
<tr>
<td>Force Distance (F-D) Spectroscopy</td>
<td>Magnetic Force Microscopy (MFM)</td>
<td>Scanning Thermal Microscopy (STMW)</td>
</tr>
<tr>
<td>Force Volume Imaging</td>
<td>Tunable Magnetic Field MFM</td>
<td></td>
</tr>
</tbody>
</table>

<table>
<thead>
<tr>
<th>Electrical Properties</th>
<th>Mechanic Properties</th>
</tr>
</thead>
<tbody>
<tr>
<td>Conductive AFM (CP-AFM)</td>
<td>Conductive AFM</td>
</tr>
<tr>
<td>ProPin™ Conductive AFM</td>
<td>ProPin™ Conductive AFM</td>
</tr>
<tr>
<td>HV Spectroscopy</td>
<td>Force Modulation Microscopy (FMM)</td>
</tr>
<tr>
<td>Kelvin Probe Force Microscopy (KPFM)</td>
<td>Nanoindentation</td>
</tr>
<tr>
<td>EFM with high voltage</td>
<td>Nanolithography</td>
</tr>
</tbody>
</table>

<table>
<thead>
<tr>
<th>Software</th>
<th>Park SmartScan™</th>
<th>Accessory</th>
</tr>
</thead>
<tbody>
<tr>
<td>PARK system control and data acquisition software</td>
<td>Temperature Controlled Stages</td>
<td>GlovesBox (Optional)</td>
</tr>
<tr>
<td>Auto-mode for quick setup and easy imaging</td>
<td>GlovesBox™</td>
<td>Allows precise control over the humidity</td>
</tr>
<tr>
<td>Manual mode for advanced use and finer scan control</td>
<td>Magnetic Field Generator</td>
<td>Making of specified gaseous environments</td>
</tr>
<tr>
<td></td>
<td>Legal/Options</td>
<td>Allowing you to insulate highly reactive materials</td>
</tr>
<tr>
<td>XBI</td>
<td></td>
<td></td>
</tr>
</tbody>
</table>

<table>
<thead>
<tr>
<th>Accessories</th>
<th></th>
</tr>
</thead>
<tbody>
<tr>
<td>Temperature Controlled Stages</td>
<td>GlovesBox™</td>
</tr>
<tr>
<td>GlovesBox™</td>
<td>Magnetic Field Generator</td>
</tr>
</tbody>
</table>

<p>| | |</p>
<table>
<thead>
<tr>
<th></th>
<th></th>
</tr>
</thead>
<tbody>
<tr>
<td>Accessories</td>
<td></td>
</tr>
<tr>
<td></td>
<td></td>
</tr>
</tbody>
</table>

- GlovesBox (Optional)
- Allows precise control over the humidity
- Making of specified gaseous environments
- Allowing you to insulate highly reactive materials

---

**Park NX12 with IOM**

![Diagram of Park NX12 with IOM](image-url)